# N-Channel Power MOSFET 100 V, 23 A, 55 m $\Omega$

#### **Features**

- Low R<sub>DS(on)</sub>
- High Current Capability
- 100% Avalanche Tested
- AEC Q101 Qualified NVD6415AN
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Para	Symbol	Value	Unit		
Drain-to-Source Volta	V <sub>DSS</sub>	100	V		
Gate-to-Source Voltage	ge – Conti	nuous	V <sub>GS</sub>	± 20	V
Continuous Drain	Steady T <sub>C</sub> = 25°C		I <sub>D</sub>	23	Α
Current R <sub>θJC</sub>	State	T <sub>C</sub> = 100°C		16	
Power Dissipation $R_{\theta JC}$	Steady State	T <sub>C</sub> = 25°C	P <sub>D</sub>	83	W
Pulsed Drain Current	tp	= 10 μs	I <sub>DM</sub>	89	Α
Operating and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	–55 to +175	°C
Source Current (Body Diode)			Is	23	Α
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 50 Vdc, $V_{GS}$ = 10 Vdc, $I_{L(pk)}$ = 23 A, L = 0.3 mH, $R_{G}$ = 25 $\Omega$ )			E <sub>AS</sub>	79	mJ
Lead Temperature for Soldering Purposes, 1/8" from Case for 10 Seconds			TL	260	°C

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Case (Drain) Steady State	$R_{\theta JC}$	1.8	°C/W
Junction-to-Ambient (Note 1)	$R_{\theta JA}$	39	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

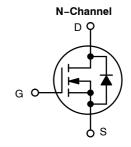
 Surface mounted on FR4 board using 1 sq in pad size, (Cu Area 1.127 sq in [2 oz] including traces).



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V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX (Note 1)
100 V	55 mΩ @ 10 V	23 A

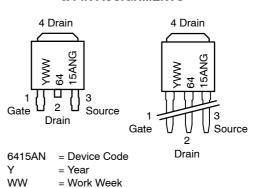




G



# MARKING DIAGRAM & PIN ASSIGNMENTS



#### **ORDERING INFORMATION**

= Pb-Free Package

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS			•		•	•	•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				113		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 100 V	T <sub>J</sub> = 25°C			1.0	μА
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> :				±100	nA
ON CHARACTERISTICS (Note 3)	'488	*DS = 3 *, *GS	- 110 (		<u>l</u>	1100	1,,,
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	· 250 µA	2.0		4.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	*GS = *DS, 'D =	. 250 μ/ (	2.0	7.6	4.0	mV/°C
Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub>	= 23 A		47	55	mΩ
Forward Transconductance	9FS	V <sub>GS</sub> = 5 V, I <sub>D</sub>	= 10 A		13		S
CHARGES, CAPACITANCES AND GA	TE RESISTANO	CE C	•			•	•
Input Capacitance	C <sub>ISS</sub>				700		pF
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MH	z, V <sub>DS</sub> = 25 V		110		
Reverse Transfer Capacitance	C <sub>RSS</sub>				52		
Total Gate Charge	Q <sub>G(TOT)</sub>				29		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 80 V, $I_{D}$ = 23 A			1.2		
Gate-to-Source Charge	$Q_{GS}$				5		
Gate-to-Drain Charge	$Q_{GD}$				14.6		
Plateau Voltage	$V_{GP}$		•		5.7		V
Gate Resistance	$R_{G}$				2.3		Ω
SWITCHING CHARACTERISTICS (Not	e 4)						
Turn-On Delay Time	t <sub>d(on)</sub>				10		ns
Rise Time	t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DE}$	<sub>0</sub> = 80 V,		37		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D = 23 \text{ A}, R_G =$	= 6.1 Ω		30		
Fall Time	t <sub>f</sub>				37		
DRAIN-SOURCE DIODE CHARACTER	RISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 23 A	$T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$		0.83 0.68	1.2	٧
Reverse Recovery Time	t <sub>RR</sub>		13 - 123 0		65		ns
Charge Time	T <sub>a</sub>	$V_{GS} = 0 \text{ V, } dI_S/dt = 100 \text{ A/}\mu\text{s,}$ $I_S = 23 \text{ A}$			46		- '''
Discharge Time	T <sub>b</sub>				19		-
Reverse Recovery Charge					176		nC
	$Q_{RR}$				170		110

- Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces).
   Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
   Switching characteristics are independent of operating junction temperatures.

## **ORDERING INFORMATION**

Device	Package	Shipping†
NTD6415ANT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD6415AN-1G	IPAK (Pb-Free)	75 Units / Rail
NVD6415ANT4G	DPAK (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

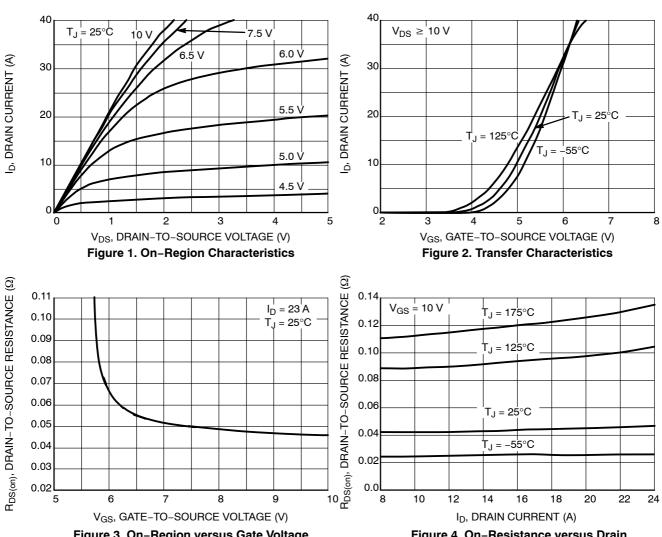
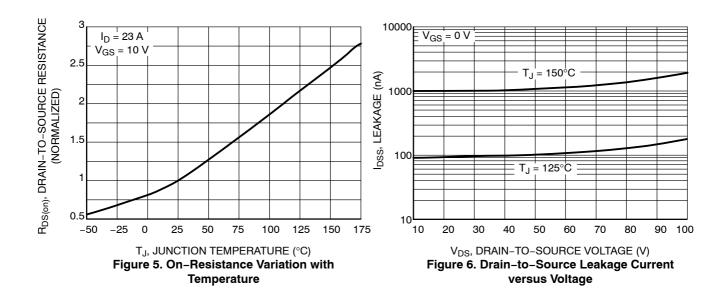
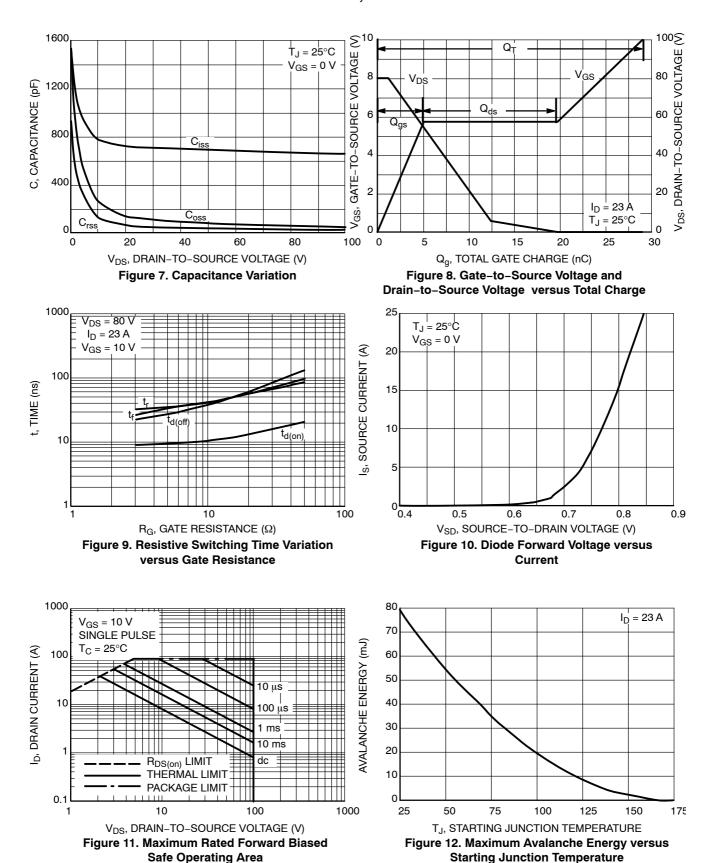


Figure 3. On-Region versus Gate Voltage

Figure 4. On-Resistance versus Drain **Current and Gate Voltage** 





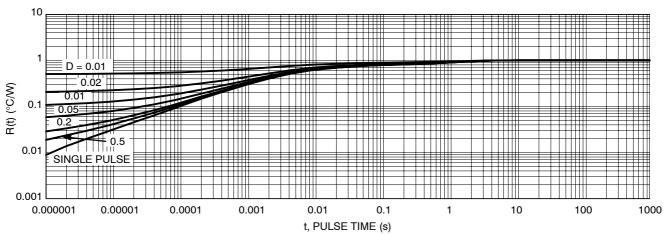
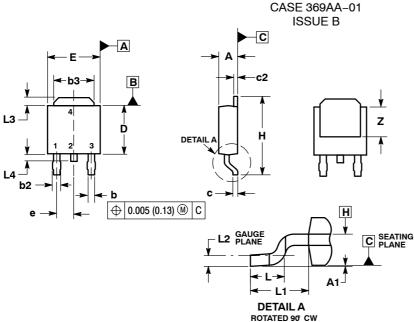


Figure 13. Thermal Response

#### PACKAGE DIMENSIONS

## **DPAK (SINGLE GUAGE)**



#### NOTES:

- IOTES:

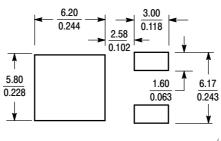
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: INCHES.
  3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.
  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
  5. DIMENSIONS, DAND E ABE DETERMINED AT THE
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
   DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29	2.29 BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108 REF		2.74 REF		
L2	0.020 BSC		0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE

DRAIN

# **SOLDERING FOOTPRINT\***

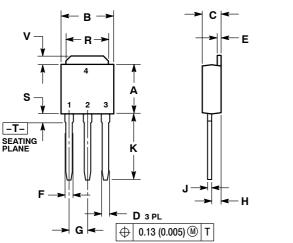


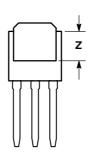
 $\left(\frac{\text{mm}}{\text{inches}}\right)$ SCALE 3:1

<sup>\*</sup>For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### PACKAGE DIMENSIONS

## IPAK CASE 369D-01 ISSUE C





#### NOTES:

- DIMENSIONING AND TOLERANCING PER
  ANSI V14 5M 1982
- ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
V	0.035	0.050	0.89	1.27
Z	0.155		3.93	

#### STYLE 2:

PIN 1. GATE

- 2. DRAIN
- 3. SOURCE
- SOURG
   DRAIN

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